

N- and P-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY						
	V _{DS} (V)	$R_{DS(on)}(m\Omega)(Typ.)$	I _D (A)	Q _g (Typ.)		
N-Channel	30	25 at V _{GS} = 10 V	4.5	10.8		
N-Chaine	30	35 at V _{GS} = 4.5 V	4.5			
P-Channel	- 30	47 at V _{GS} = - 10 V	2	6		
r-onalliel	- 30	$68 \text{ at V}_{GS} = -4.5 \text{ V}$	- 3	0		

FEATURES

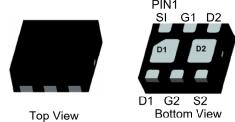
- DT-Trench Power MOSFET
- \bullet 100 % R_g and UIS tested
- Low Gate Charge

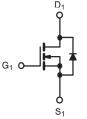


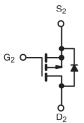
APPLICATIONS

- Load Switch
- Battery Protection









N-Channel MOSFET

P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _A = 25 °C, unless otherwise noted)						
PARAMETER	SYMBOL	N-Channel	P-Channel	UNIT		
Drain-Source Voltage	V_{DS}	30	- 30	V		
Gate-Source Voltage		V_{GS}	± 20	± 20	V	
Continuous Drain Current (T, j = 150 °C) ^a	T _A = 25 °C	I_	4.5	- 3	Α	
Continuous Drain Current (1) = 130 °C)	T _A = 100 °C	- I _D	3.2	- 2.1		
Pulsed Drain Current ^b		I _{DM}	20	- 12		
Maximum Power Dissipation ^C	T _A = 25 °C	В	2.5	1.25	W	
waximum Fower Dissipation-	T _A = 100 °C	- P _D	1	0.5	VV	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to +150		°C		

THERMAL RESISTANCE RATINGS							
		N-Channel	P-Channel				
Parameter	Symbol	LIMITE	LIMITE	Unit			
Maximum Junction-to-Ambient ^d	R _{thJA}	50	100	°C/W			

Notes

- a. Calculated continuous current based on maximum allowablejunction temperature.
- b. Repetitive rating; pulse width limited by max. junction temperature.
- c. Pd is based on max. junction temperature, using junction-case thermal resistance.
- d. The value of R_{BJA} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper,in a still air environment with Ta=25 °C.



PARAMETER	SYMBOL TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V_{DS} $V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30	-	-	V	
Gate Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.0	-	3	V	
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA	
Zero Gate Voltage Drain Current	,	V _{DS} = 30 V, V _{GS} = 0 V		-	1		
Zero date voltage Drain Current	I _{DSS}	V _{DS} = 24 V, V _{GS} = 0 V, T _J = 55 °C	-	- 20		μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 V$, $V_{GS} = 5 V$	4.5	-	-	Α	
Drain-Source On-State Resistance a	D	$V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}$	-	25	30	mΩ	
Diani-Source On-State Hesistance	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 2 \text{ A}$	-	35	48		
Forward Transconductance ^a	g _{fs}	$V_{DS} = 5 \text{ V}, I_{D} = 3 \text{ A}$	-	9.5	-	S	
Dynamic ^b							
Input Capacitance	C _{iss}		-	428	-	pF	
Output Capacitance	C _{oss}	V _{GS} = 0 V, V _{DS} = 15 V, f = 1 MHz	-	74	-		
Reverse Transfer Capacitance	C _{rss}		-	62	-		
Total Gate Charge ^c	Qg		-	10.8	-	nC	
Gate-Source Charge ^c	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}$	-	0.7	-		
Gate-Drain Charge ^c	Q _{gd}		-	1.6	-		
Gate Resistance	R_g	f = 1 MHz	-	3.05	-	Ω	
Turn-On Delay Time ^c	t _{d(on)}		-	4	-		
Rise Time ^c	t _r	$V_{DS} = 15 \text{ V}, I_D = 3 \text{ A}, R_g = 2.5 \Omega$	-	4.5	-		
Turn-Off Delay Time ^c	t _{d(off)}	V _{GS} = 10 V	-	25	-	ns	
Fall Time ^c	t _f		-	6	-		
Drain-Source Body Diode Ratings and	Characterist	tics ^b (T _A = 25 °C)					
Continuous Source-Drain Diode Current	Is	T _C = 25 °C	-	-	4.5	Α	
Pulsed Current (t = 100 µs)	I _{SM}		-	-	20	Α	
Forward Voltage ^a	V _{SD}	I _F = 1 A, V _{GS} = 0 V	-	-	1.2	V	
Reverse Recovery Time	t _{rr}			7.5	-	ns	
Reverse Recovery Charge	Q _{rr}	$I_F = 3 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s}$	-	3.9	_	nC	

Notes

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static				<u>'</u>			
Drain-Source Breakdown Voltage	V_{DS} $V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$		- 30	-	-	V	
Gate Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 0.5	-	- 2.5	V	
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA	
Zero Gate Voltage Drain Current		V _{DS} = - 30 V, V _{GS} = 0 V -		-	- 1	μА	
Zero Gate Voltage Drain Gurrent	I _{DSS}	V _{DS} = - 24 V, V _{GS} = 0 V, T _J = 55 °C	20		- 20		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5$, $V_{GS} = -5$ V	- 3	-	-	Α	
Drain-Source On-State Resistance a	Book	V _{GS} = - 10 V, I _D = - 2 A	-	47	56		
Drain-Source On-State Nesistance	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 1.5 A	-	68	85	mΩ	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 5 V, I _D = - 2 A	-	5	-	S	
Dynamic ^b							
Input Capacitance	C _{iss}		-	570	-	pF	
Output Capacitance	C _{oss}	V _{GS} = 0 V, V _{DS} = - 15 V, f = 1 MHz	-	76	-		
Reverse Transfer Capacitance	C _{rss}		-	64	-		
Total Gate Charge ^c	Q_g		-	5.5	-		
Gate-Source Charge c	Q _{gs}	V _{DS} = - 15 V, V _{GS} = - 10 V, I _D = - 2 A		0.5	-	nC	
Gate-Drain Charge ^c	Q _{gd}		-	1.2	-		
Gate Resistance	R_g	f = 1 MHz	-	15	-	Ω	
Turn-On Delay Time ^c	t _{d(on)}		-	6	-		
Rise Time ^c	t _r	$V_{DS} = -15 \text{ V}, I_{D} = -2 \text{ A}, R_{g} = 2.5 \Omega$	-	8	-	- ns	
Turn-Off Delay Time ^c	t _{d(off)}	V _{GS} = - 10 V	-	14	-		
Fall Time ^c	t _f		-	9	-		
Drain-Source Body Diode Ratings and	Characterist	cics ^b (T _A = 25 °C)					
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C	-	-	- 3	Α	
Pulsed Current (t = 100 μs)	I _{SM}		-	-	- 12	Α	
Forward Voltage ^a	V _{SD}	I _F = - 1 A, V _{GS} = 0 V	-	-	- 1.2	V	
Reverse Recovery Time	t _{rr}	I _F = - 2 A, di/dt = 100 A/µs	-	15	-	ns	
Reverse Recovery Charge			-	4.5	-	nC	

Notes

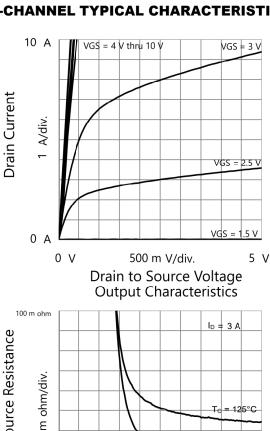
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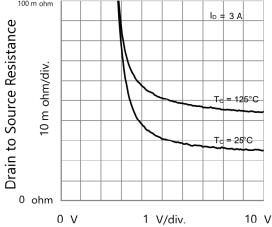
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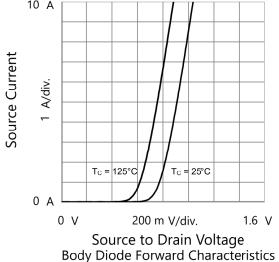


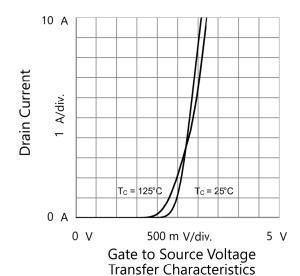
N-CHANNEL TYPICAL CHARACTERISTICS (T_A = 25 °C, unless otherwise noted)

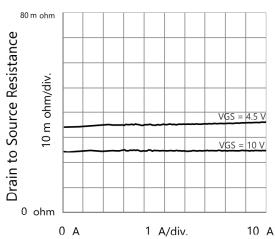


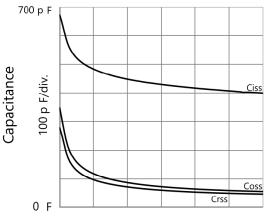


Gate to Source Voltage Drain to Source Resistance vs. Gate to Source Voltage 10 A







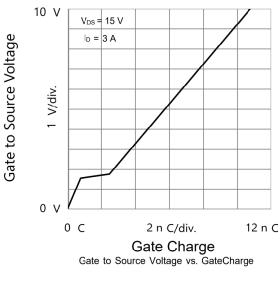


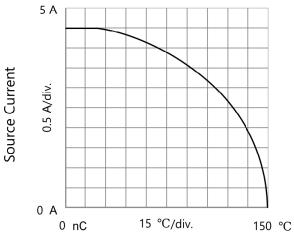
0 V 5 V/div. 30 V Drain to Source Voltage Capacitances

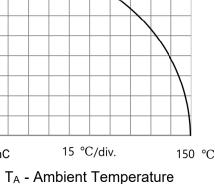
Drain Current Drain to Source Resistance vs. Drain Current

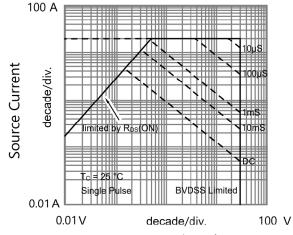


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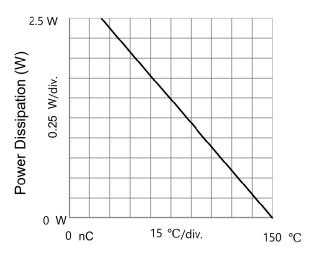




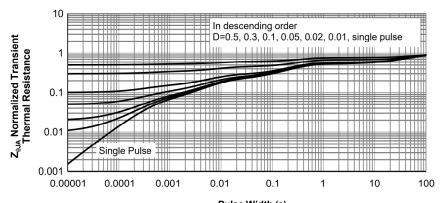




Source to Drain Voltage Safe Operating Area, Junction-to-Ambient



T_A - Ambient Temperature

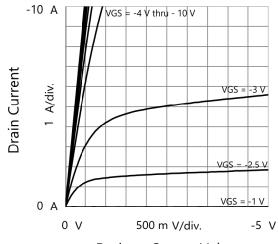


Pulse Width (s)
Normalized Maximum Transient Thermal Impedance

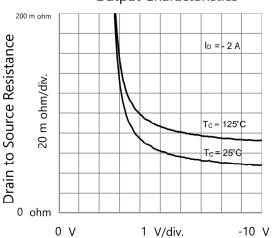


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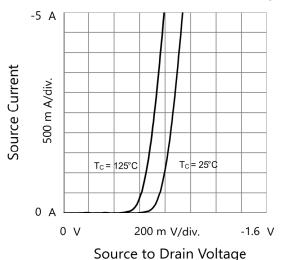
P-CHANNEL TYPICAL CHARACTERISTICS (T_A = 25 °C, unless otherwise noted)



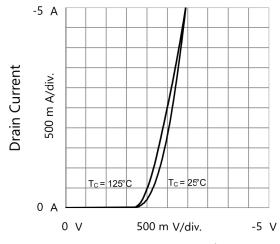
Drain to Source Voltage Output Characteristics



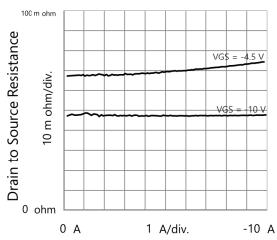
Gate to Source Voltage
Drain to Source Resistance vs. Gate to Source Voltage



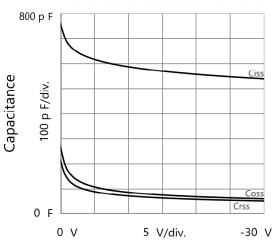
Body Diode Forward Characteristics



Gate to Source Voltage Transfer Characteristics



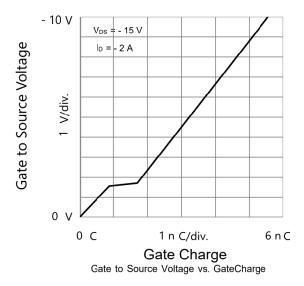
Drain Current
Drain to Source Resistance vs. Drain Current



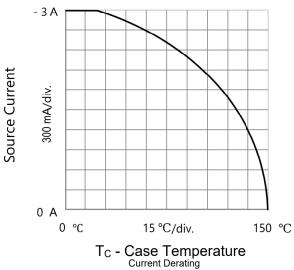
Drain to Source Voltage Capacitances

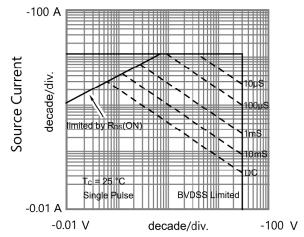
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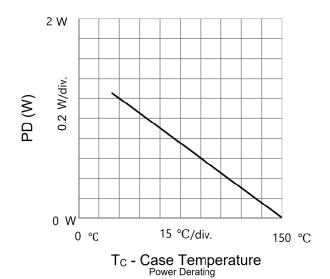


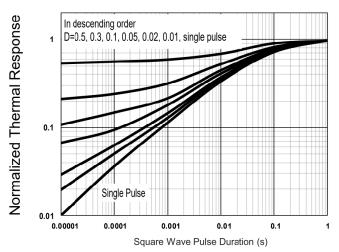
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Source to Drain Voltage
Safe Operating Area, Junction-to-Ambient

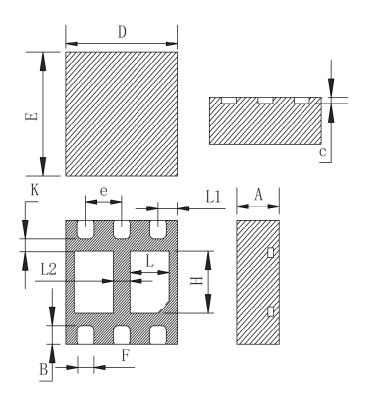




Normalized Thermal Transient Impedance



DFN 2X2-D PACKAGE OUTLINE



COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

Symbol	Min	Тур	Max
A	0.70	0.75	0.80
В	0.20	0.30	0.40
С	0.153	0.203	0.253
D	1.90	2.00	2.10
Е	1.90	2.00	2.10
e	0.55	0.65	0.70
F	0.20	0.30	0.40
Н	0.85	1.00	1.10
L	0.55	0.70	0.80
L1	0.25	0.35	0.45
L2	0.20	0.30	0.40
K	0.15	0.20	0.30





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